and the terms of an APO is a sanctionable violation. This determination is issued and published in accordance with sections 751(a)(1) and 777(i)(1) of the Act.

Dated: May 15, 2007.

David M. Spooner,

Assistant Secretaryfor Import Administration.

#### Appendix – Issues in Decision Memorandum

1. Simplified Reporting and Further– Manufactured Imports

2. G&A expenses

3. Constructed Export Price (CEP) Profit Rate

4. Offsetting Dumped Sales with Non– Dumped Sales

5. Classification of JIT Deliveries as CEP Sales

6. Duty Absorption

7. Warranty Expenses

8. Clerical Errors

[FR Doc. E7–9815 Filed 5–21–07; 8:45 am] BILLING CODE 3510–DS–S

## **DEPARTMENT OF COMMERCE**

### National Institute of Standards and Technology

## Notice of Prospective Grant of Exclusive Patent License

**AGENCY:** National Institute of Standards and Technology, Commerce.

SUMMARY: This is a notice in accordance with 35 U.S.C. 209(c)(1) and 37 CFR 404.7(a)(1)(i) that the National Institute of Standards and Technology ("NIST"), U.S. Department of Commerce, is contemplating the grant of an exclusive license in the United States of America, its territories, possessions and commonwealths, to NIST's interest in the invention embodied in U.S. Patent No. 5,620,857 (Application No. 08/ 473,979), titled "Optical Trap for Detection and Quantitation of Subzeptomolar Quantities of Analytes," NIST Docket No. 94–042US to Haemonetics Corporation, having a place of business at 400 Wood Road, Braintree, Massachusetts 02184–9114. The grant of the license would be for the field of use: Chemical and biological material sensing and measurement for medical diagnostics.

**FOR FURTHER INFORMATION CONTACT:** J. Terry Lynch, National Institute of Standards and Technology, Office of Technology Partnerships, 100 Bureau Drive, Stop 2200, Gaithersburg, MD 20899, Phone 301–975–2691.

**SUPPLEMENTARY INFORMATION:** The prospective exclusive license will be royalty bearing and will comply with the terms and conditions of 35 U.S.C. 209 and 37 CFR 404.7. The prospective exclusive license may be granted unless, within thirty days from the date of this published Notice, NIST receives written evidence and argument which establish that the grant of the license would not be consistent with the requirements of 35 U.S.C. 209 and 37 CFR 404.7. The availability of the invention for licensing was published in the **Federal Register** on June 24, 2003.

U.S. Patent No. 5,620,857 is owned by the U.S. government, as represented by the Secretary of Commerce. Tightly focused beams of laser light are used as "optical tweezers" to trap and manipulate polarizable objects such as microspheres of glass or latex with diameters on the order of 4.5 .mu.m. When analytes are allowed to adhere to the microspheres, small quantities of these analytes can be manipulated, thus allowing their detection and quantitation even when amounts and concentrations of the analytes are extremely small. Illustrative examples include measuring the strength needed to break antibody-antigen bonds and the detection of DNA sequences.

Dated: May 16, 2007.

James M. Turner,

Deputy Director.

[FR Doc. E7–9826 Filed 5–21–07; 8:45 am] BILLING CODE 3510–13–P

#### DEPARTMENT OF COMMERCE

# National Institute of Standards and Technology

[Docket No.: 070427102-7103-01]

#### Request for Technical Input— Standards in Trade Workshops

**AGENCY:** National Institute of Standards and Technology, Commerce. **ACTION:** Request for workshop recommendations.

**SUMMARY:** The National Institute of Standards and Technology (NIST) invites interested parties to submit recommendations for workshops covering specific sectors and targeted countries or regions of the world where training in the U.S. system of standards development, conformity assessment, and metrology may facilitate trade. Prospective workshops will be scheduled for a one week period. This notice is not an invitation for proposals to fund grants, contracts or cooperative agreements of any kind. NIST will offer a limited number of workshops, based upon the availability of resources. Recommenders are encouraged to consider Administration priorities outlined in the 2006 National Export Strategy. NIST will consider recommendations based upon which workshops would be most useful to intended audiences.

**DATES:** All recommendations must be submitted no later than 5 p.m., June 21, 2007.

ADDRESSES: All recommendations must be submitted to Ellen Emard via email(*ellen.emard@nist.gov*) or by mail to 100 Bureau Drive, Mail Stop 2100, Gaithersburg, MD 20899. The National Export Strategy is available at *http:// www.ita.doc.gov/media/publications/*. Additional information about the NIST Standards in Trade Workshops, including schedules and summary reports for workshops held to date and participant information, is available at *http://ts.nist.gov/standards/global/ sitdescr.cfm*.

## FOR FURTHER INFORMATION CONTACT:

Ellen Emard (301) 975–4038, ellen.emard@nist.gov.

**SUPPLEMENTARY INFORMATION:** The Standards in Trade Workshops are a major activity of the Global Standards and Information Group in the NIST Standards Services Division. The workshops are designed to provide timely information to foreign standards officials on U.S. practices in standards and conformity assessment. Participants are introduced to U.S. technology and principles in metrology, standards development and application, and conformity assessment systems and procedures.

Each workshop is a one week program offering an overview of the roles of the U.S. Government, private sector, and regional and international organizations engaged in standards development and conformity assessment practices. Specific workshop objectives are to: (1) Familiarize participants with U.S. technology and practices in metrology, standardization, and conformity assessment; (2) describe and understand the roles of the U.S. Government and the private sector in developing and implementing standards; (3) understand the structure of the standards and conformity assessment systems in the invited country or countries and the role and responsibilities of organizations